Index of Claims

Application/Control No.	Applicant(s)/Patent Under Reexamination
10791629	LEE ET AL.
Examiner	Art Unit
Jermele M Hollington	2829

✓	Rejected	•	Cancelled
=	Allowed	÷	Restricted

N	Non-Elected
ı	Interference

Α	Appeal
0	Objected

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☐ Claims renumbered in the same order as presented by applicant						□ СРА	□ т.с). 🔲 R.1.47		
CLA	IM					DATE				
Final	Original	06/17/2005	04/06/2006	09/26/2006	12/21/2006	05/31/2007	11/13/2007	05/15/2008		
	37	÷	✓	✓	✓	✓	✓	✓		
	38	÷	N	-	-	-	-	-		
	39	÷	-	-	-	-	-	-		
	40	÷	✓	✓	✓	✓	✓	✓		
	41	÷	✓	✓	✓	✓	✓	✓		
	42	÷	✓	✓	✓	✓	✓	✓		

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